

United States Patent [19]

Shintani

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[54] **TWIN-NIBBED MARKING INSTRUMENT**

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[**] Term: **14 Years**

[21] Appl. No.: **43,198**

[22] Filed: **Apr. 24, 1987**

[52] U.S. Cl. **D19/36; D19/41;**
D19/43; D19/51

[58] Field of Search **D19/35, 36, 41-51,**
D19/54-58; 401/17, 18, 34, 195

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 247,246	2/1978	Verona	D19/45
D. 279,992	8/1985	Gribb	D19/43
196,270	10/1897	Trask	401/18 X
1,479,996	1/1924	Lundmark	401/17 X

1,710,130 4/1929 Wiese 401/17
4,600,327 7/1986 Guzman 401/18

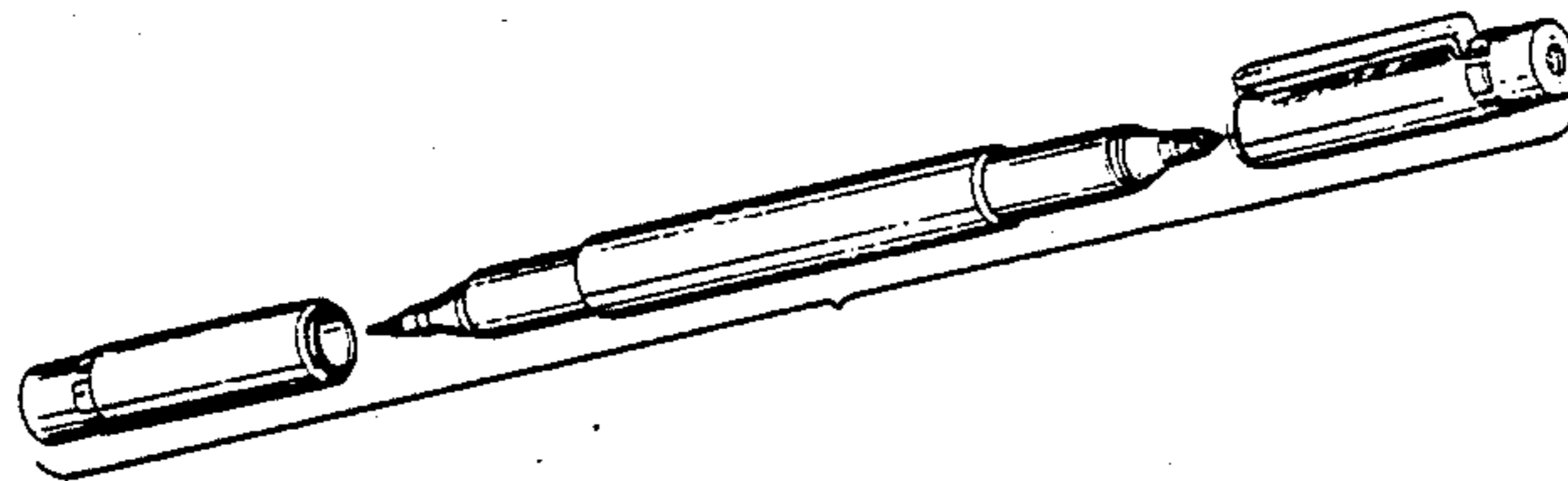
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[57] **CLAIM**

The ornamental design for a twin-nibbed marking instrument, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of a twin-nibbed marking instrument showing my new design;
FIG. 2 is a rear elevational view;
FIG. 3 is a right side elevational view;
FIG. 4 is a left side elevational view;
FIG. 5 is a top plan view;
FIG. 6 is a bottom plan view; and
FIG. 7 is a perspective view on a reduced scale in an exploded condition.



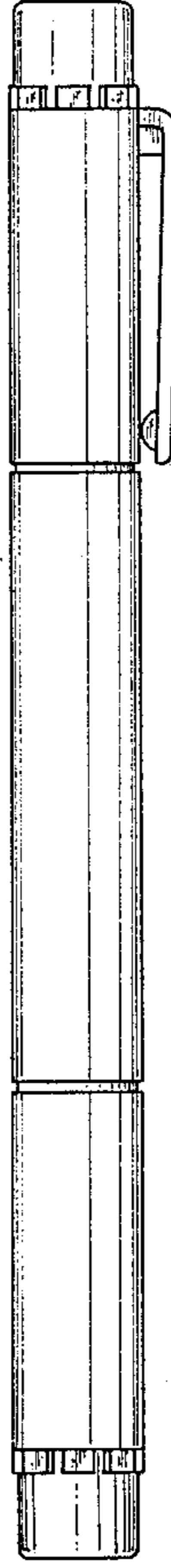
FIG_2



FIG_1



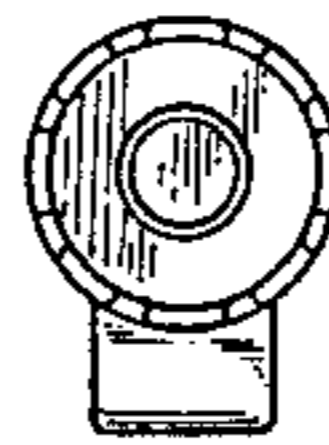
FIG_4



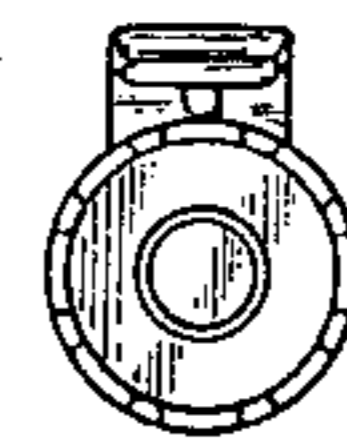
FIG_3



FIG_5



FIG_6



FIG_7

